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(54) **Title:** DEFECT DETECTION MODEL TRAINING METHOD AND APPARATUS, AND ELECTRONIC DEVICE

(54) 发明名称: 缺陷检测模型的训练方法、装置及电子设备

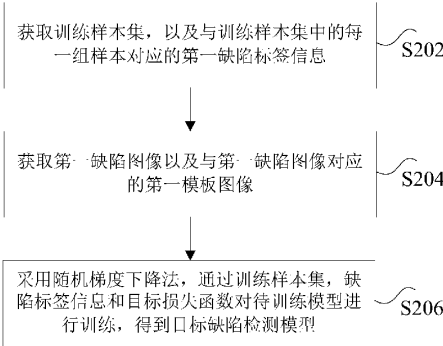


图 2

- S202 Obtain a training sample set and first defect label information corresponding to each group of samples in the training sample set
- S204 Obtain a defect image and a first template image corresponding to the defect image
- S206 Utilizing a stochastic gradient descent method, and by means of the training sample set, the defect label information, and the target loss function, train a model to be trained, and obtain a target defect detection model

(57) **Abstract:** The present application discloses a defect detection model training method and apparatus, and an electronic device. The method comprises: obtaining a training sample set and first defect label information corresponding to each group of samples in the training sample set, wherein each group of samples in the training sample set comprises a defect image and a template image corresponding to the defect image, and the first defect label information comprises first category information and first position information for each defect in the defect image; determining a target loss function; utilizing a stochastic gradient descent method, and by means of the training sample set, the defect label information, and the target loss function, training a model to be trained, and obtaining a target defect detection model, wherein the target defect detection model is used for determining defect position information and defect category information in an image containing defects to be detected.

(57) 摘要: 本申请公开了一种缺陷检测模型的训练方法、装置及电子设备。其中, 该方法包括: 获取训练样本集, 以及与训练样本集中的每一组样本对应的第一缺陷标签信息, 其中, 训练样本集中的每一组样本包括缺陷图像, 以及与缺陷图像对应的模板图像, 第一缺陷标签信息包括缺陷图像中各处缺陷的第一类别信息和第一位置信息; 确定目标损失函数; 采用随机梯度下降法, 通过训练样本集, 缺陷标签信息和目标损失函数对待训练模型进行训练, 得到目标缺陷检测模型, 其中, 目标缺陷检测模型用于确定待检测缺陷图像中的缺陷位置信息和缺陷类别信息。

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— 包括国际检索报告(条约第21条(3))。